

<b>INFORMATION DISCLOSURE STATEMENT TRANSMITTAL</b>		<b>Application Number</b>	10/586218
To Commissioner For Patents		<b>Filing Date</b>	
Enclosed herewith is a Form PTO-1449, any required copies of documents listed thereon, and any concise explanation of their relevance is indicated below per 37 CFR 1.97.		<b>First Named Inventor</b>	MARINISSEN, ERIK J.
		<b>Group Art Unit</b>	
		<b>Examiner Name</b>	
		<b>Atty. Docket Number</b>	NL040065US1

<b>U.S. PATENT DOCUMENTS</b>					
Examiner Initials*	Cite No. <sup>1</sup>	Document Number No.-Kind Code <sup>2</sup> (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns Lines, Where Relevant Passages or Relevant Figures Appear
		US-			
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<b>FOREIGN PATENT DOCUMENTS</b>					
Examiner Initials*	Cite No. <sup>1</sup>	Document Number (ctry <sup>3</sup> -no. <sup>4</sup> -kind <sup>5</sup> , if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of cited document	Pages, Columns Lines, Where Relevant Passages or Relevant Figures Appear
					T <sup>6</sup>

<b>NON-PATENT LITERATURE DOCUMENTS</b>					
Examiner Initials*	Cite No. <sup>1</sup>	Include name of the author (in capital letters), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.			T <sup>6</sup>
	1	WAAYERS T ED - INSTITUTE OF ELECTRICAL AND ELECTRONICS ENGINEERS: "AN IMPROVED TEST CONTROL ARCHITECTURE AND TEST CONTROL EXPANSION FOR CORE-BASED SYSTEM CHIPS"; PROCEEDINGS INTERNATIONAL TEST CONFERENCE 2003. (ITC); CHARLOTTE NC. SEPT. 30, OCT. 2, 2003; INTERNATIONAL TEST CONF. N.Y.: IEEE US VOL. 1, 30 SEPT 2003; PP 1145-1154			
	2	ZORIAN Y ET AL: "TESTING EMBEDDED-CORE BASED SYSTEM CHIPS"; PROCEEDINGS INTERNATIONAL TEST CONFERENCE 1998 (IEEE CAT. NO. 98CH36270) INT. TEST CONF. WASHINGTON DC USA; ONLINE 23 OCT. 1998 (1998-10-23) PP 130-143.			

Examiner Signature		Date Considered	
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\* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

<sup>1</sup> Unique citation designation number. <sup>2</sup> See attached Kinds of U.S. Patent Documents. <sup>3</sup> Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). <sup>4</sup> For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. <sup>5</sup> Kind of document by the appropriate symbol as indicated on the document under WIPO Standard ST. 16 if possible. <sup>6</sup> Applicant is to place a check mark here if English language Translation is attached.